

Formation of metal wire arrays via electrodeposition in pores of Si, Ge and III–V semiconductors

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Abstract

Deep straight macropores in n-type Si have been completely filled with copper (Cu). Homogeneous metal deposition inside the deep pores was achieved by means of electroplating using a solution containing only CuSO₄ mixed with H₂SO₄ and an optimized process that begins at the bottom of the pores. Pores as deep as 150 μm could be filled without encountering the so-called “bottleneck” effect. Straight macropores with diameters below 100 nm and extreme aspect ratios in InP could be filled with Cu using a pulsed process. Interconnected pores extending in the available set of 111 directions in 100 GaAs and forming domains could not be filled with Cu; instead the volume occupied by the pore domain was completely filled with Cu; i.e. the porous structure was destroyed. A possible reason for this new effect will be given.